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Technical Data

RF Power Field Effect Transistor

N-Channel Enhancement-Mode Lateral MOSFET

RF Power transistor designed for applications operating at frequencies between 1030 and 1090 MHz, 1% to 20% duty cycle. This device is suitable for use in pulsed applications.

• Typical Pulsed Performance: V_{DD} = 50 Volts, I_{DQ} = 250 mA, P_{out} = 250 Watts Peak (25 W Avg.), f = 1090 MHz, Pulse Width = 100 μ sec, Duty Cycle = 10% Power Gain — 21 dB

Power Gain — 21 dB Drain Efficiency — 60%

 Capable of Handling 10:1 VSWR, @ 50 Vdc, 1090 MHz, 250 Watts Peak Power

Features

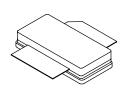
- Characterized with Series Equivalent Large-Signal Impedance Parameters
- · Internally Matched for Ease of Use
- Qualified Up to a Maximum of 50 V_{DD} Operation
- · Integrated ESD Protection
- Greater Negative Gate-Source Voltage Range for Improved Class C Operation
- RoHS Compliant
- In Tape and Reel. R3 Suffix = 250 Units per 56 mm, 13 inch Reel.

Document Number: MRF6V10250HS Rev. 2, 4/2010

VD-UC

MRF6V10250HSR3

1090 MHz, 250 W, 50 V PULSED LATERAL N-CHANNEL RF POWER MOSFET



CASE 465A-06, STYLE 1 NI-780S

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	-0.5, +100	Vdc
Gate-Source Voltage	V _{GS}	-6.0, +10	Vdc
Storage Temperature Range	T _{stg}	- 65 to +150	°C
Case Operating Temperature	T _C	150	°C
Operating Junction Temperature (1,2)	TJ	225	°C

Table 2. Thermal Characteristics

Characteristic		Value (2,3)	Unit
Thermal Resistance, Junction to Case			
Case Temperature 79°C, 250 W Pulsed, 100 μsec Pulse Width, 10% Duty Cycle	$Z_{\theta JC}$	0.10	°C/W

- 1. Continuous use at maximum temperature will affect MTTF.
- 2. MTTF calculator available at http://www.freescale.com/rf. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.
- 3. Refer to AN1955, *Thermal Measurement Methodology of RF Power Amplifiers*. Go to http://www.freescale.com/rf. Select Documentation/Application Notes AN1955.





Table 3. ESD Protection Characteristics

Test Methodology	Class
Human Body Model (per JESD22-A114)	2 (Minimum)
Machine Model (per EIA/JESD22-A115)	B (Minimum)
Charge Device Model (per JESD22-C101)	IV (Minimum)

Table 4. Electrical Characteristics (T_A = 25°C unless otherwise noted)

I _{GSS}	_	_	500	nAdc
V _{(BR)DSS}	100	_	_	Vdc
I _{DSS}	_		50	μAdc
I _{DSS}	_	_	2	mA
	V _{(BR)DSS}	V _{(BR)DSS} 100	V _{(BR)DSS} 100 —	V _{(BR)DSS} 100 — — — 50

Gate Threshold Voltage $(V_{DS} = 10 \text{ Vdc}, I_D = 528 \mu\text{Adc})$	V _{GS(th)}	1	1.8	3	Vdc
Gate Quiescent Voltage $(V_{DD} = 50 \text{ Vdc}, I_D = 250 \text{ mAdc}, Measured in Functional Test})$	V _{GS(Q)}	2	2.4	3	Vdc
Drain-Source On-Voltage (V _{GS} = 10 Vdc, I _D = 1.32 Adc)	V _{DS(on)}		0.25		Vdc

Dynamic Characteristics (1)

Reverse Transfer Capacitance (V _{DS} = 50 Vdc ± 30 mV(rms)ac @ 1 MHz, V _{GS} = 0 Vdc)	C _{rss}	_	0.8	_	pF
Output Capacitance (V _{DS} = 50 Vdc ± 30 mV(rms)ac @ 1 MHz, V _{GS} = 0 Vdc)	C _{oss}		340	_	pF
Input Capacitance (V _{DS} = 50 Vdc, V _{GS} = 0 Vdc ± 30 mV(rms)ac @ 1 MHz)	C _{iss}	_	280	_	pF

 $\textbf{Functional Tests} \ (In \ Freescale \ Test \ Fixture, 50 \ ohm \ system) \ V_{DD} = 50 \ Vdc, \ I_{DQ} = 250 \ mA, \ P_{out} = 250 \ W \ Peak \ (25 \ W \ Avg.), \ f = 1090 \ MHz, \ P_{OUT} = 1000 \ MHz, \ P_{OUT} = 10000 \ MHz, \ P_{OUT} = 10000 \ MHz, \ P_{OUT} = 10000 \ MHz, \ P_{OUT} =$ Pulsed, 100 μsec Pulse Width, 10% Duty Cycle

_						
	Power Gain	G _{ps}	19	21	23	dB
	Drain Efficiency	η_{D}	55	60	_	%
	Input Return Loss	IRL	_	-12	-9	dB

^{1.} Part internally matched both on input and output.



Figure 1. MRF6V10250HSR3 Test Circuit Schematic

Table 5. MRF6V10250HSR3 Test Circuit Component Designations and Values

	Part	Description	Part Number	Manufacturer	
4	C1	240 pF Chip Capacitor	ATC100B241JT500XT	ATC	1
	C2, C9, C11	1.8 pF Chip Capacitors	ATC100B1R8CT500XT	ATC	
	C3	3.3 pF Chip Capacitor	ATC100B3R3CT500XT	ATC	
	C4, C5	5.1 pF Chip Capacitors	ATC100B5R1CT500XT	ATC	l
	C6, C10, C12	39 pF Chip Capacitors	ATC100B390JT500XT	ATC	
	C7, C15	2.2 μF, 50 V Chip Capacitors	C1825C225J5RAC	Kemet	1
	C8	4.7 pF Chip Capacitor	ATC100B4R7CT500XT	ATC	l
	C13, C14	470 μF, 63 V Electrolytic Capacitors	EKME633ELL471MK25S	Multicomp	-
	L1	5 nH, 2 Turn Inductor	A02TKLC	Coilcraft	
	L2	7 nH, Hand Wound	2T, 18awg	Freescale	
Т	R1	10 Ω, 1/4 W Chip Resistor	CRCW120610R0FKEA	Vishay	l
4	R2	20 Ω, 1 W Chip Resistor	CRCW251220R0FKEA	Vishay	



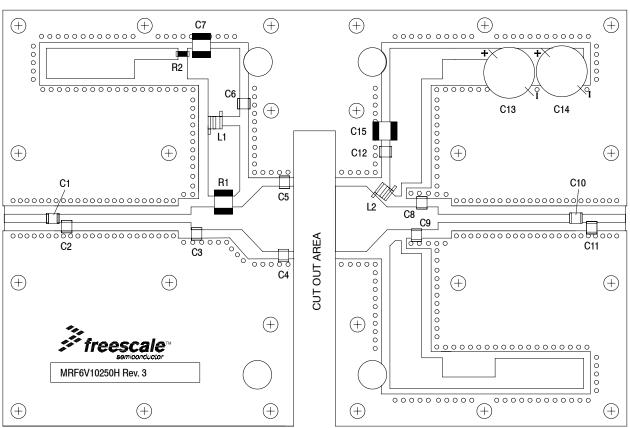


Figure 2. MRF6V10250HSR3 Test Circuit Component Layout



TYPICAL CHARACTERISTICS

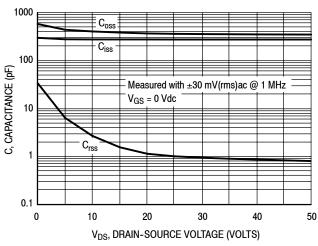


Figure 3. Capacitance versus Drain-Source Voltage

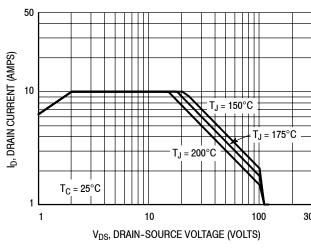


Figure 4. DC Safe Operating Area

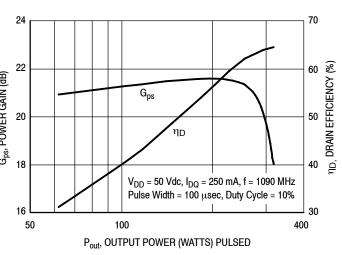


Figure 5. Pulsed Power Gain and Drain Efficiency versus Output Power

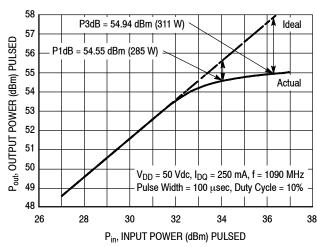


Figure 6. Pulsed Output Power versus Input Power

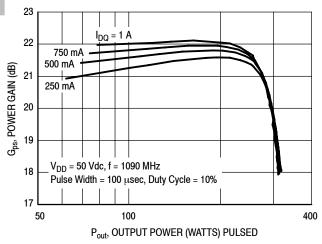


Figure 7. Pulsed Power Gain versus Output Power

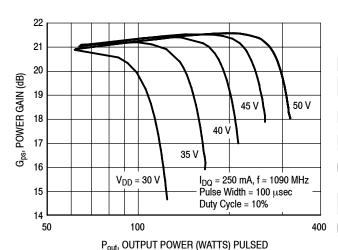


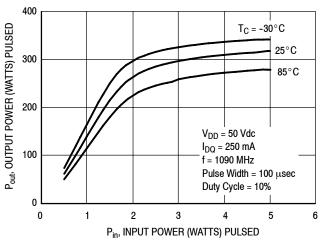
Figure 8. Pulsed Power Gain versus Output Power

MRF6V10250HSR3



TYPICAL CHARACTERISTICS

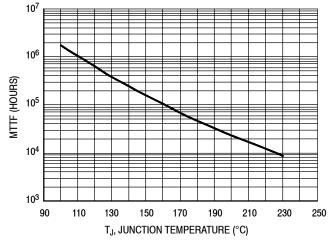
24



70

Figure 9. Pulsed Output Power versus Input Power

Figure 10. Pulsed Power Gain and Drain Efficiency versus Output Power

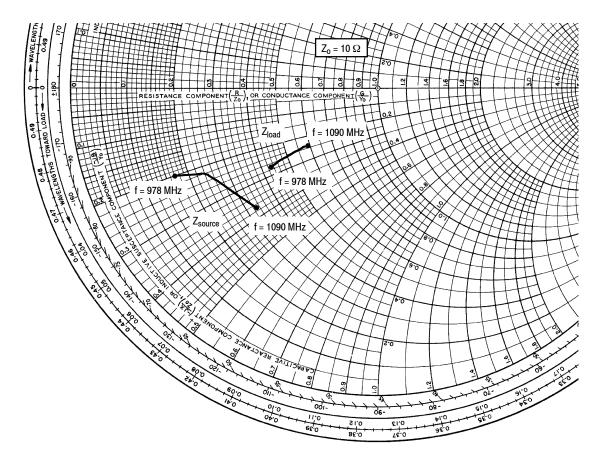


This above graph displays calculated MTTF in hours when the device is operated at $V_{DD}=50$ Vdc, $P_{out}=250$ W Peak, Pulse Width = 100 μ sec, Duty Cycle = 10%, and $\eta_{D}=60\%$.

MTTF calculator available at http://www.freescale.com/rf. Select Software & Tools/Development Tools/Calculators to access MTTF calculators by product.

Figure 11. MTTF versus Junction Temperature





 V_{DD} = 50 Vdc, I_{DQ} = 250 mA, P_{out} = 250 W Peak

f MHz	Z _{source} Ω	Z _{load} Ω
978	1.67 - j2.04	4.3 - j2.72
1030	2.39 - j2.23	5.66 - j2.42
1090	3.26 - j3.72	5.85 - j2.39

Z_{source} = Test circuit impedance as measured from gate to ground.

Z_{load} = Test circuit impedance as measured from drain to ground.

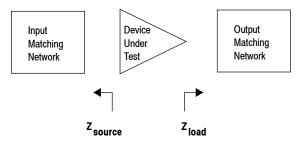
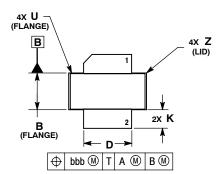
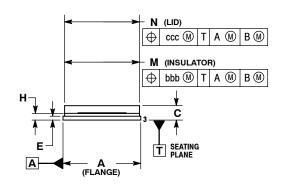


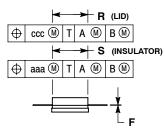
Figure 12. Series Equivalent Source and Load Impedance



PACKAGE DIMENSIONS







- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1994.
 2. CONTROLLING DIMENSION: INCH.
 3. DELETED
 4. DIMENSION H IS MEASURED 0.030 (0.762) AWAY FROM PACKAGE BODY.

	INC	HES	MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.805	0.815	20.45	20.70
В	0.380	0.390	9.65	9.91
С	0.125	0.170	3.18	4.32
D	0.495	0.505	12.57	12.83
E	0.035	0.045	0.89	1.14
F	0.003	0.006	0.08	0.15
Н	0.057	0.067	1.45	1.70
K	0.170	0.210	4.32	5.33
M	0.774	0.786	19.61	20.02
N	0.772	0.788	19.61	20.02
R	0.365	0.375	9.27	9.53
S	0.365	0.375	9.27	9.52
U		0.040		1.02
Z		0.030		0.76
aaa	0.005 REF		0.127	'REF
bbb	0.010	REF	0.254	REF
ccc	0.015	REF	0.381	REF

STYLE 1: PIN 1. DRAIN 2. GATE 5. SOURCE

CASE 465A-06 ISSUE H NI-780S



PRODUCT DOCUMENTATION AND SOFTWARE

Refer to the following documents to aid your design process.

Application Notes

· AN1955: Thermal Measurement Methodology of RF Power Amplifiers

Engineering Bulletins

• EB212: Using Data Sheet Impedances for RF LDMOS Devices

Software

• Electromigration MTTF Calculator

For Software, do a Part Number search at http://www.freescale.com, and select the "Part Number" link. Go to the Software & Tools tab on the part's Product Summary page to download the respective tool.

REVISION HISTORY

The following table summarizes revisions to this document.

Revision	Date	Description	L
0	Feb. 2008	Initial Release of Data Sheet	
1	June 2008	 Added 25 W Avg. to Typical Pulsed Performance bullet, p. 1 Added Pulsed to Fig. 6, Pulsed Output Power versus Input Power Y axis label to better clarify performance, p. 5 Corrected Fig. 9 title to read: Pulsed Output Power versus Input Power, p. 6 	
2	Apr. 2010	 Operating Junction Temperature increased from 200°C to 225°C in Maximum Ratings table and related "Continuous use at maximum temperature will affect MTTF" footnote added, p. 1 Reporting of pulsed thermal data now shown using the Z_{θJC} symbol, p. 1 Added Electromigration MTTF Calculator availability to Product Software, p. 9 	

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